

Physics 195 / Applied Physics 195 — Assignment #8

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Due: 12:45pm + 10 min grace period, Nov. 21, 2017 at the dropbox outside Maxwell-Dworkin Room 131.

Problem 1 (200 pt): *pn* junction

(a) A silicon *pn* junction has $N_a = 10^{17} \text{ cm}^{-3}$ on the *p* side, and $N_d = 10^{16} \text{ cm}^{-3}$ on the *n* side. At 300K, calculate the chemical potential μ for each region, and draw the equilibrium band diagram. Find the built-in potential V_0 from the diagram.

(b) Show that the small-signal capacitance C of a semiconductor *pn* junction with doping densities N_a and N_d in the *p* and *n* regions with bias voltage V (which can be positive for forward bias and negative for reverse bias) is given by

$$C(V) = \frac{A}{2} \left[\frac{N_a N_d}{N_a + N_d} \times \frac{2e\epsilon}{V_0 - V} \right]^{1/2} \quad (1)$$

where A is the cross-sectional area of the *pn*-junction, ϵ is the electric permittivity of the semiconductor, and V_0 is the built-in potential. This problem involves solving the electrostatics equation (Poisson equation) in the depletion region of the *pn* junction. When the depletion region stores total charges of $\pm Q(V)$ for a given bias voltage V , the small-signal capacitance is given by $C = |dQ/dV|$.

(c) Consider a silicon *pn* junction with doping densities of $N_a = 8 \times 10^{15}/\text{cm}^3$ in the *p*-region and $N_d = 1 \times 10^{17}/\text{cm}^3$ in the *n*-region. Calculate the depletion layer depth into the *p*-region, depletion layer depth into the *n*-region, and maximum electric field strength within the depletion layer, at biases of -5 V (reverse bias), 0 V , and 0.3 V (forward bias). Plot the capacitance $C(V)$ of the *pn*-junction as a function of the bias voltage V , assuming that the cross-sectional area of the *pn*-junction is $25 \mu\text{m}^2$. The silicon electric permittivity is $\epsilon \approx 12\epsilon_0$ where $\epsilon_0 = 8.854 \times 10^{-12} \text{ F/m}$.

(d) Consider a semiconductor *pn* junction in equilibrium. The conduction band electron concentration will decrease as you walk from the *n*-region to *p*-region. Therefore, one could first think of an electron diffusion current in the conduction band, which would flow from the *n*-region to the *p*-region. The magnitude of this electron diffusion current density would be expressed as

$$|J_{diff}(x)| = \left| eD_n \frac{dn(x)}{dx} \right| \quad (2)$$

where D_n is the diffusion constant of conduction band electrons, x is the spatial coordinate along the *pn* junction, and $n(x)$ is the conduction band electron concentration at position x . Now, the electric field in the depletion region opposes the diffusion of electrons. This may be thought of as an opposite-direction conduction band electron drift current that would cancel the electron diffusion current. The magnitude of the drift current density would be expressed as

$$|J_{drift}(x)| = |en(x)v_n(x)| = |en(x)\mu_n E(x)| \quad (3)$$

where $v_n(x)$ is the drift velocity of electrons at position x , μ_n is the mobility of electrons, and $E(x)$ is the electric field at position x . Using $|J_{diff}(x)| = |J_{drift}(x)|$ in equilibrium, derive the celebrated Einstein relation: $D_n/\mu_n = k_B T/e$.

Problem 2 (50 pt): bipolar junction transistor

Consider a p^+np bipolar junction transistor with p^+ region called emitter, *n* region base, and *p* region collector. Draw the equilibrium energy band diagram. Also draw the band diagram when the p^+n junction is forward biased and the *np* junction reverse biased. Under this bias arrangement (called forward active bias), explain the transport of the charge carriers, drawing what is similar to the top figure on page 5 of Lecture #17.